

USN



CMR INSTITUTE OF TECHNOLOGY

Internal Assessment Test - I

Sub:	VLSI DESIGN					Code:	ISBC72	
Date:	30.10.2023	Duration:	90 mins	Max Marks:	50	Sem:	VII	Branch:
Answer Any Five Questions								
Questions						Marks	OBG	
							CO RBT	
1.	Explain the operation of an n-channel enhancement mode MOSFET with neat diagrams.					[10]	CO1 L1	
2.	Derive the expression for Drain to source current for an n-channel MOSFET in all three regions.					[10]	CO1 L2	
3.	Describe in detail about any five non-ideal I-V characteristics of MOS transistor.					[10]	CO1 L1	

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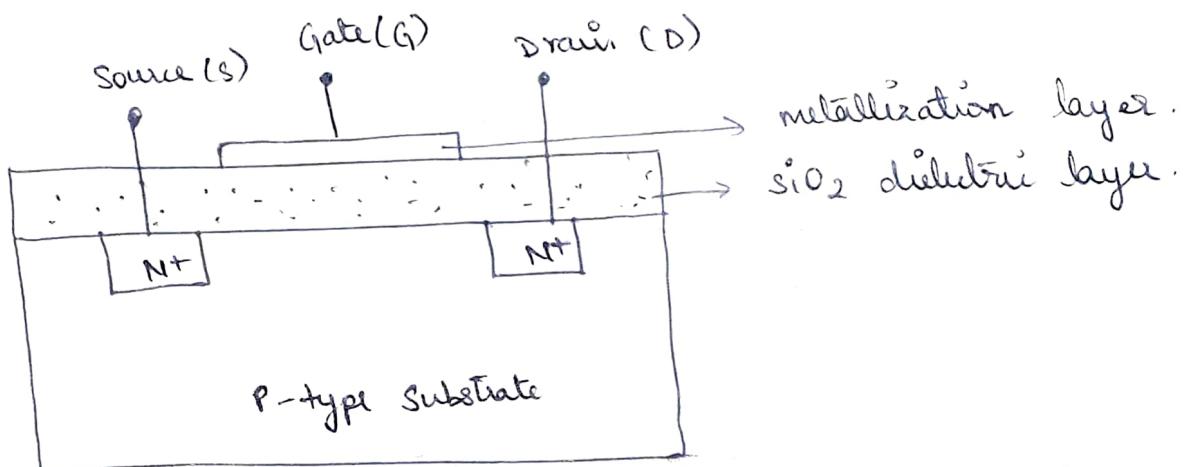
4.	Realize the following logic expression using CMOS: a) $Y = \overline{(A.B)} + (C.D)$ b) $Y = \overline{A} + \overline{B}C$	[10]	CO1 L2	
5.	Illustrate with neat sketch, explain the DC transfer characteristics of CMOS inverter.	[10]	CO1 L2	
6.	With necessary circuit diagram, explain the operation of transmission gate. Also realize a 4:1 multiplexer using transmission gate.	[10]	CO1 L3	

CI

CCI

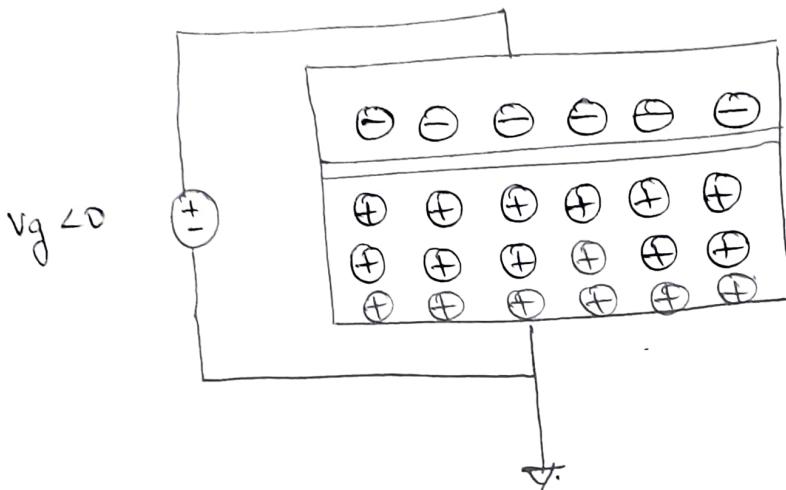
HOD

- Q1) Basic structure of n-channel enhancement mode MOSFET is shown below.



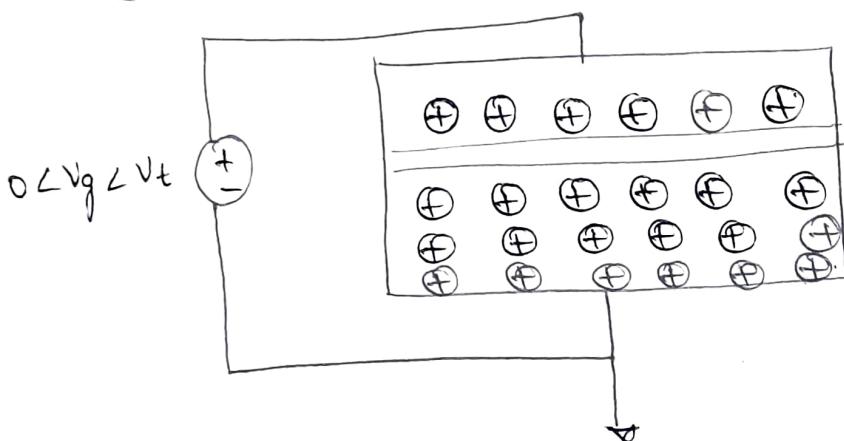
- When the gate voltage is zero ($V_g = 0$) and no positive voltage is applied across between the source and drain (V_{ds}), the PN-junction is reverse-biased.
- Since there is no current-flow across the substrate and region below the gate, MOSFET is in OFF condition.
- When a positive voltage is applied to the gate i.e. when the gate to source voltage increases, it induces an electric field E across the substrate which attracts electrons and repels holes.
- At this condition, when the gate voltage is increased further, the gate of p-type changes to n-type.
- Based on applied voltage, there are 3 modes of operation.

(i) Accumulation Mode:



- when the gate voltage is equal to 0 ($V_g = 0$) or voltage less than 0 is applied to the gate (-ve voltage), electrons get accumulated at the region below the gate.
- This mode is known as accumulation mode.
- There is no conduction between the drain & source.
- The device is in OFF condition.

(ii) Depletion Mode:

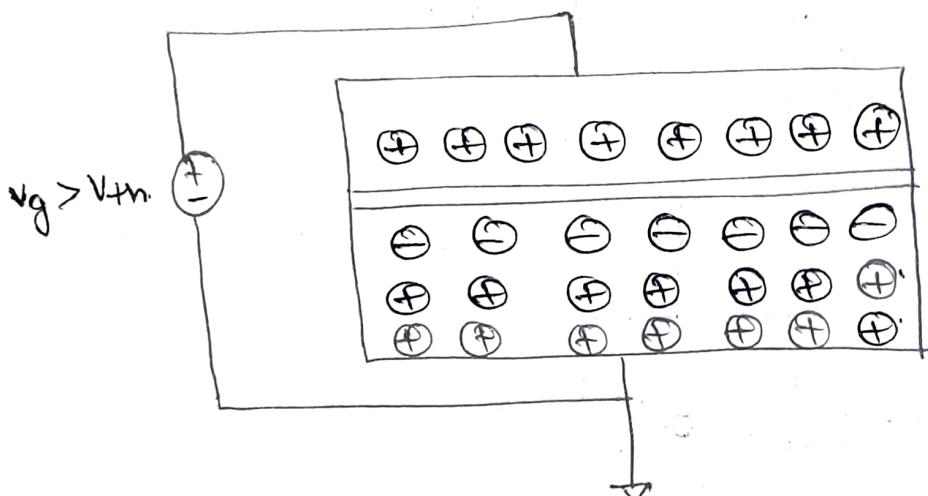


- when voltage greater than 0 but less than threshold voltage is applied to the gate, it is known as depletion mode.

- The electrons get attracted towards the gate and holes are repelled towards the region under gate.
- This creates a depletion layer in the region below the gate and hence is known as depletion mode.

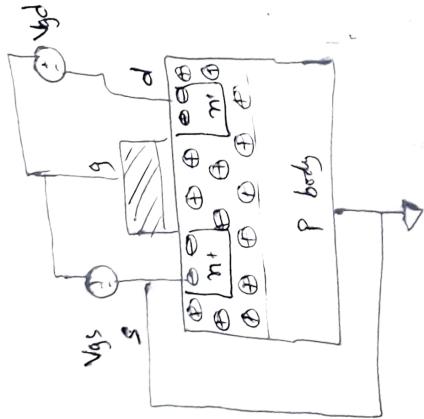
(iii) Inversion Mode.

Condition



Cut off
Line
Schematic

- when the positive voltage is increased further i.e. when the gate voltage is raised above threshold voltage, the electrons are attracted towards the substrate.
- The holes are repelled towards the gate.
- At this stage, on increasing the voltage p-type changes to n-type.
- Conduction takes place in this mode.
- Since electrons are attracted towards substrate & holes are repelled towards gate, an inversion layer is created.



$$V_{gs} < V_t$$

$\rightarrow V_{gs} < V_t$

\rightarrow Transistor is in off state.

\rightarrow The junction between drain and source is open.

thus no current flows

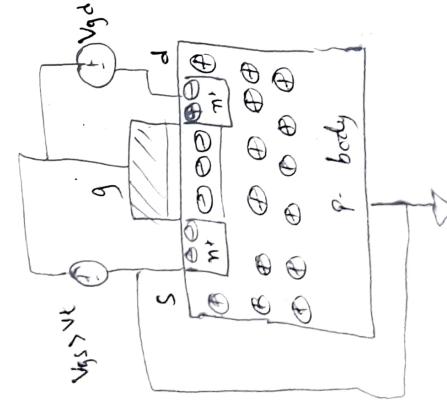
\rightarrow It is called cut off region.

$$V_{gs} < V_t$$

$\rightarrow I_{ds} = 0$.

\rightarrow Also there is no channel formed.

\rightarrow Source is grounded.



$$V_{gs} > V_t$$

$$V_{gs} = V_{gd}$$

\rightarrow The channel layer is formed b/w drain and source. Called inversion layer below the gate.

$$V_{ds} = 0.$$

- iii) Linear Region.
-
- $V_{gs} > V_t$
- $V_{ds} = V_{gs} - V_{gd}$
- $V_{ds} \rightarrow 0$
- $V_{gs} = V_{gd}$
- \rightarrow The E-field pushes J_{ds} from drain to source.
- \rightarrow This form a channel between source and drain called linear region.

iv) Saturation Region

-
- $V_{gs} > V_t$
- $V_{gd} > V_t$ (Saturation)
- $V_{ds} > V_t$
- \rightarrow When $V_{ds} > V_{gs} - V_t$ it forms saturation region, where the layer gets pinched off towards the source.
- \rightarrow Some positive drop voltage is still present there cause e^- to flow.

Ans2.)

In cut off region $V_{GS} < V_t$
there is no current flowing. $\therefore \boxed{I_{DS} = 0}$.
cut off.

$$Q = CV - \textcircled{1}$$

$$C = C_g : \text{or } WL \cdot \textcircled{2} \quad (\text{Total capacitance})$$

$$C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$$

$$V = V_g - V_t - \textcircled{3}$$

$$V_g = \frac{V_{GS} + V_{DS}}{2} - \textcircled{4}$$

$$V_{DS} = V_{GS} - V_{DS} - \textcircled{5}$$

$$\therefore V_{GD} = V_{GS} - V_{DS} - \textcircled{6}$$

putting \textcircled{6} in \textcircled{4}

$$V_g = \frac{2V_{GS} - V_{DS}}{2} \Rightarrow V_g = V_{GS} - \frac{V_{DS}}{2} - \textcircled{7}$$

$$\text{Also } V = V_{GS} - \frac{V_{DS}}{2} - V_t - \textcircled{8}$$

$V = \mu E$ (charge velocity)

$$t = \frac{L}{V} = \frac{L}{\mu E}$$

$$E = \frac{V_{DS}}{L}$$

$$I = \frac{Q}{t}$$

$$I_{DS} = \frac{C_g V}{t}$$

$$I_{ds} = \frac{C_o \times W \times L}{\mu C} \left(V_{gs} - \frac{V_{ds}}{2} - V_t \right)$$

$$= C_o \times W \times L \left(V_{gs} - \frac{V_{ds}}{2} - V_t \right)$$

$$= C_o \times W \times L \left[I_d = \frac{V_{ds}}{L} \right]$$

$$\boxed{I_{ds} = C_o \times W \times \frac{V_{ds}}{L} \left(V_{gs} - \frac{V_{ds}}{2} - V_t \right)}$$

for saturation region

$$V_{ds} = V_{gs} - V_t$$

$$\therefore I_{ds\text{ sat}} = \beta V_{ds} \left(V_{gs} - \frac{V_{ds}}{2} - V_t \right) \\ = \beta \left(V_{gs} - V_t \right) \left(\left(V_{gs} - V_t \right) - \left(\frac{V_{gs} - V_t}{2} \right) \right)$$

$$\boxed{I_{ds} = \frac{\beta}{2} \left(V_{gs} - V_t \right)^2}$$

→ Saturation region

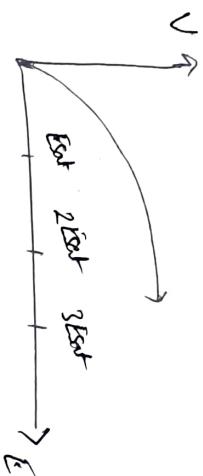
$$\beta = \frac{C_o \times W \times L}{\mu C}$$

i) Charge mobility

$$V = \mu \vec{E}$$

$\rightarrow \mu$ is a constant term.

\rightarrow If \vec{E} increases, then μ also increased which in turn increases the electron mobility. Note is ' V ' at E_{sat} .



\rightarrow If V is not saturated

$$J_{ds} = \frac{\mu C_{ox} W}{2} (V_{GS} - V_t)^2$$

\rightarrow If V is saturated

$$J_{ds} = \mu C_{ox} W (V_{GS} - V_t) V_{GS}$$

\rightarrow From above eqn it can be seen that if V is saturated it is quadratically dependent and for saturation it is linearly dependent.

Mobile generation

- When the ion charge moves in the direction of length of separation it get attracted to a surface than it the mobility
- If mobility is decreased the ion also get reduced that is called mobile generation

Thermal ions generation

- It is movement of ions but if the electron beyond negative side is also affected
- This reduces the channel length due to recombination reaction
- Ion current is decrease in T
- Ion current is off set

$$I = I_0 e^{-\frac{qU}{kT}}$$

$$\frac{I}{I_0} = e^{-\frac{qU}{kT}}$$
$$\ln \frac{I}{I_0} = -\frac{qU}{kT}$$

$$\frac{I}{I_0} = e^{-\frac{qU}{kT}}$$

- Intrinsic carrier density $N_i = N_D + N_A$
- $N_i = N_D + N_A$

v) Body Effect

- When potential between body and source is reduced it also affect the V_t .
- Thus when V_t is also reduced it is called body effect.
- Transistor has 4th implicit terminal called body.

$$V_t = V_{to} + \gamma (\sqrt{\phi_s - V_{SB}} - \sqrt{\phi_s})$$

- This equation gives the V_t dependence on γ

γ → Body pot. coefficient.

V_{to} → Pot when V_t is at saturation

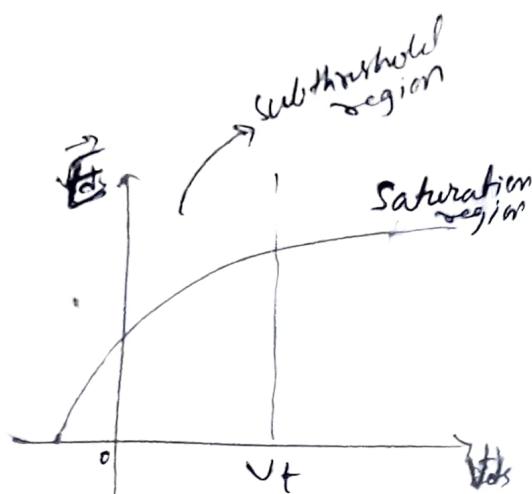
ϕ_s : pot when body ~~saturation~~.

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v) Junction Leakage

- It is the leakage current when there is saturation.

vi) Sub-threshold region

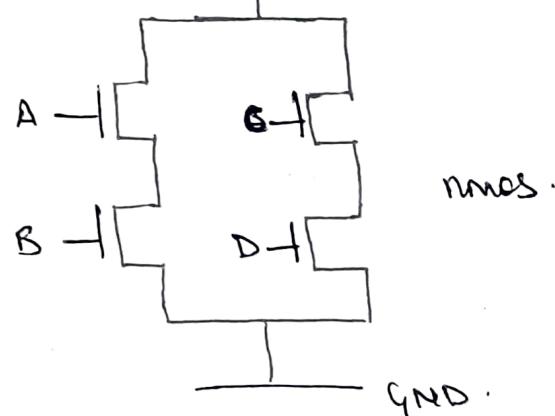
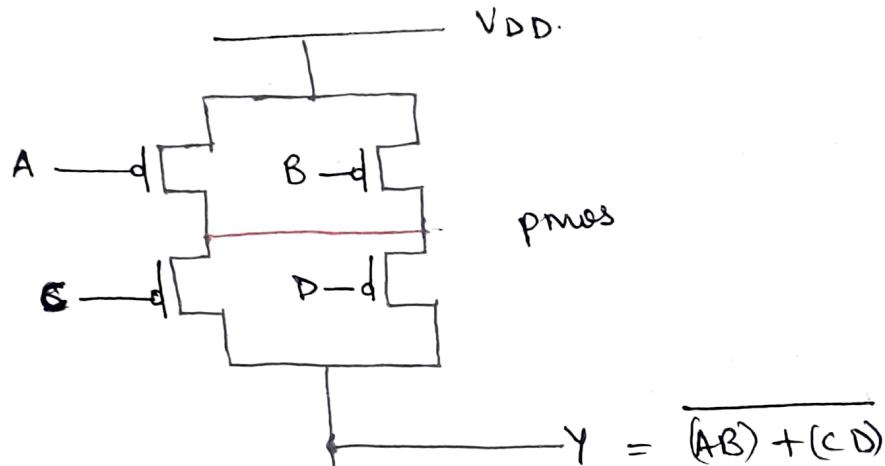


Q4)

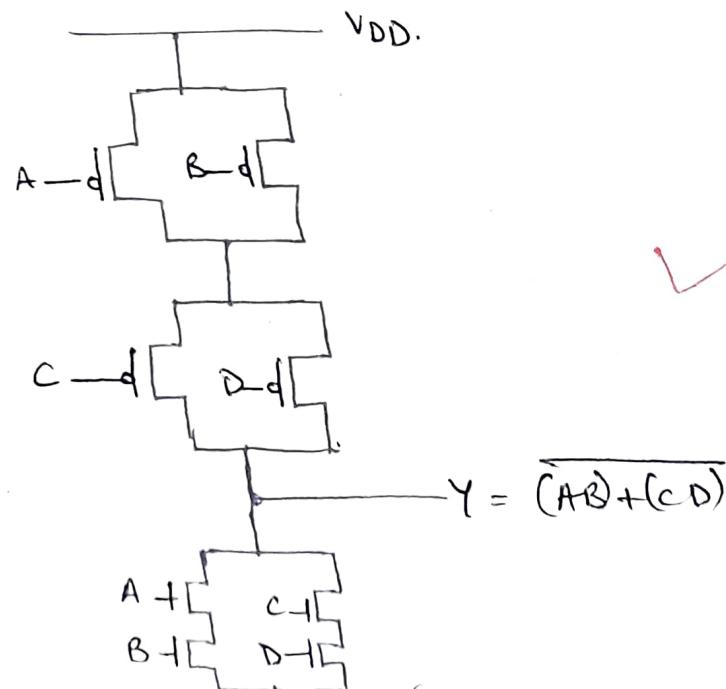
$$(a) Y = \overline{(AB)} + (CD)$$

nmos
and - series
or - parallel

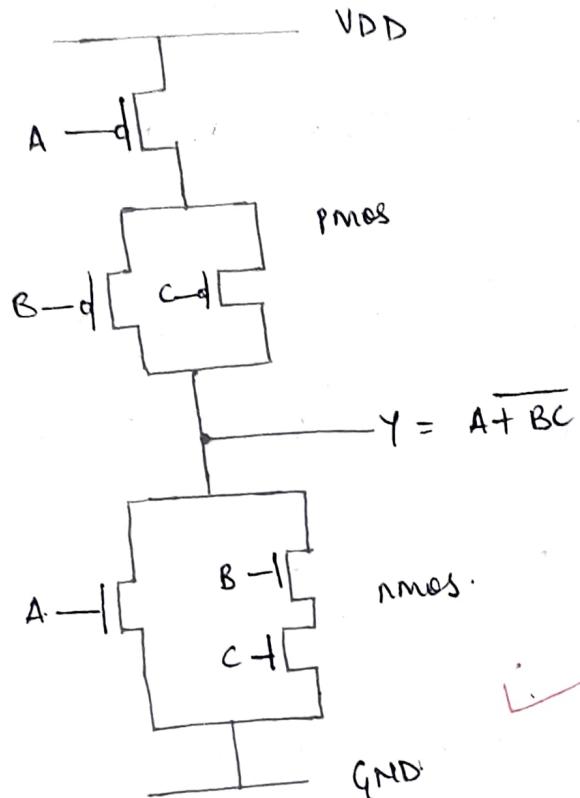
pmos
and - parallel
or - series



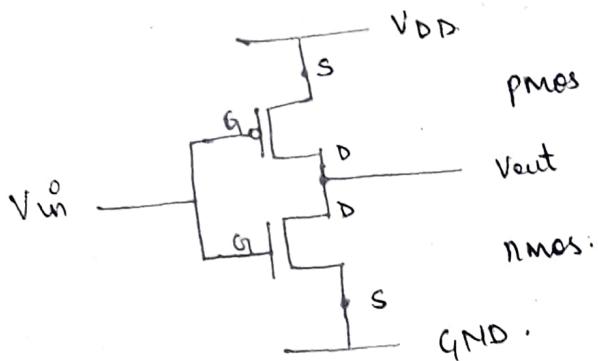
or



$$(b) Y = \overline{A + BC}$$



Q5) \rightarrow DC transfer characteristics of CMOS inverter relates to the output voltage to the input voltage.



CMOS structure

- \rightarrow The threshold voltage of pmos (V_{tp}) is always negative.
- \rightarrow The threshold voltage of nmos (V_{tn}) is always positive.

For nodes:

$$V_{gen} = (V_g - V_s)_+ = V_d - 0 = \underline{\underline{V_{in}}}$$

$$V_{dnn} = (V_d - V_s)_+ = V_{out} - 0 = \underline{\underline{V_{out}}}$$

For power:

$$V_{gsp} = (V_g - V_s)_p = V_d - \underline{\underline{V_{DD}}}$$

$$V_{dpp} = (V_d - V_s)_p = V_{out} - \underline{\underline{V_{DD}}}$$

* Regions of operation for power and nodes:

for nodes:

$$V_{gen} < V_d \rightarrow \text{Int-eff region}$$

$$V_{gen} > V_d \rightarrow \text{either saturation or linear}$$

$$\rightarrow V_{dnn} < V_{gen} - V_d \rightarrow \text{linear region}$$

$$\rightarrow V_{dnn} \geq V_{gen} - V_d \rightarrow \text{saturation region}$$

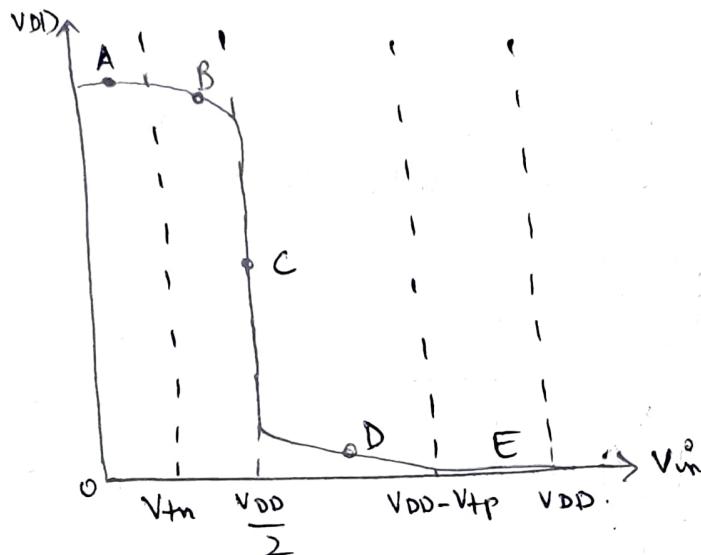
for power:

$$V_{gsp} > V_d \rightarrow \text{Int-eff region}$$

$$V_{gsp} < V_d \rightarrow \text{either saturation or out-eff}$$

$$\rightarrow V_{dpp} > V_{gsp} - V_d \rightarrow \text{linear region}$$

$$\rightarrow V_{dpp} \leq V_{gsp} - V_d \rightarrow \text{saturation region}$$



Region	nmos	pmos
A	cut-off	linear
B	saturation	linear
C	saturation	saturation
D	linear	saturation
E	linear	cut-off

In region A: pmos transistor is on and pulls the o/p to V_{DD} . nmos transistor is OFF. (cut-off region).

In region B: nmos transistor starts to turn ON, pulling the output down. (saturation region).

In region C: Both the transistors are in saturation region.

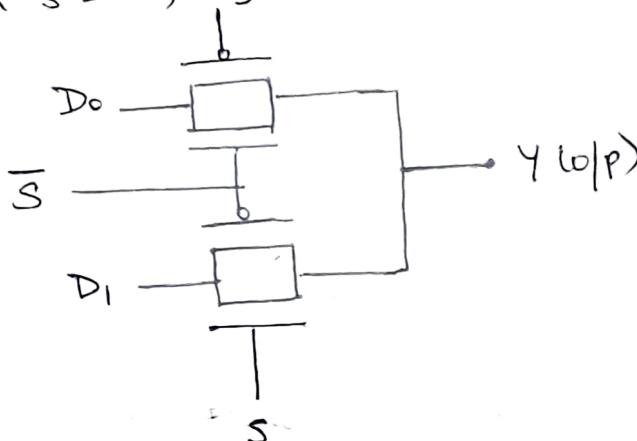
In region D: The pmos transistor is partially ON.

In region E: pmos transistor is OFF. Hence the nmos transistor drives / pulls the output down to 0.

Q6)

transmission gate

In this example, selection line $s=0$ selects D_0 as the o/p. and when $s=1$, it selects D_1 as the o/p.

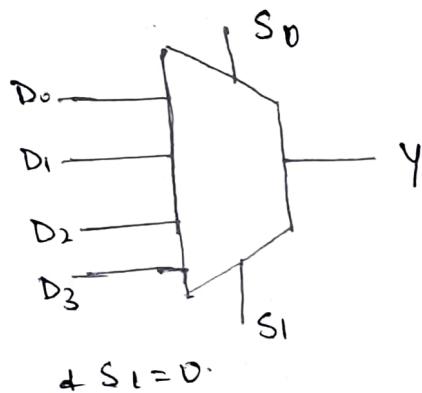


S	Y
0	D_0
1	D_1

This is a transmission gate for a 2:1 MUX.

Incase of 4:1 MUX :

→ There are 4 inputs and 2 selection lines with 1



$S_0, S_1 = 0$	Y.
0, 0, 0	D_0
0, 0, 1	D_1
1, 0, 0	D_2
1, 0, 1	D_3

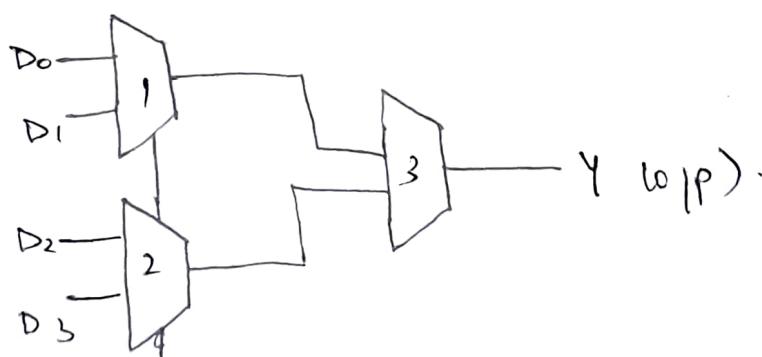
$$+ S_1 = 0$$

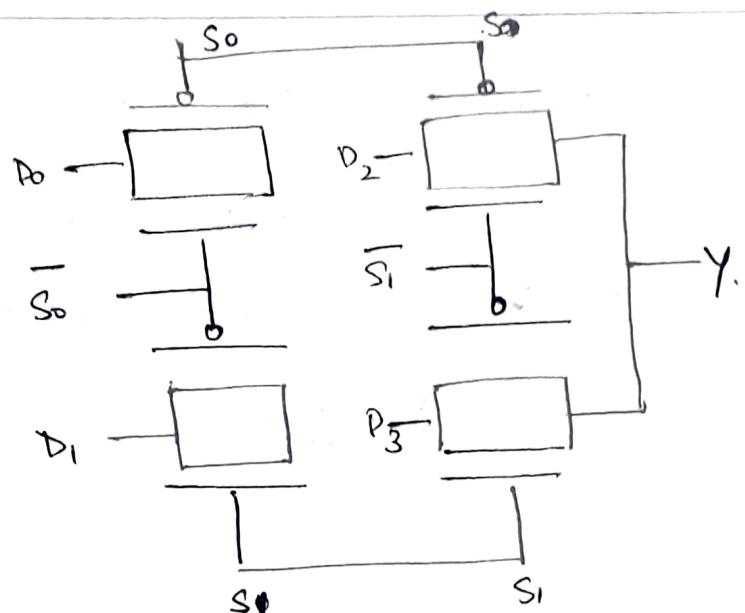
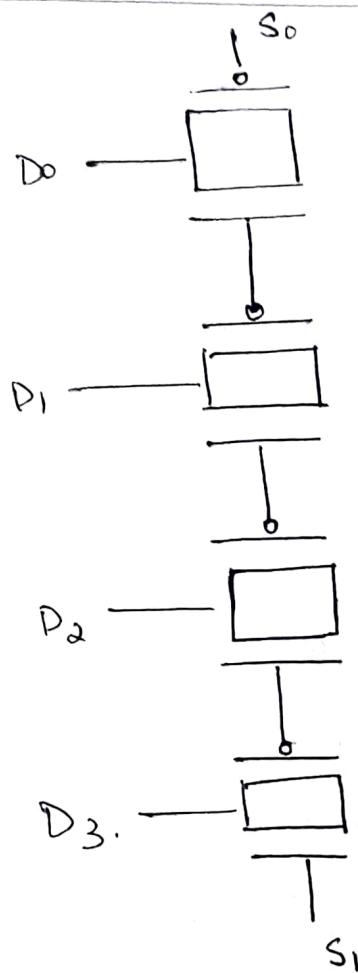
→ when $S_0 = 0$ & $S_1 = 0$, the i/p D_0 is directed as output.

→ when $S_0 = 0$ & $S_1 = 1$, the i/p D_1 is selected and directed as o/p

→ when $S_0 = 1$ & $S_1 = 0$, the i/p D_2 is selected and directed as o/p

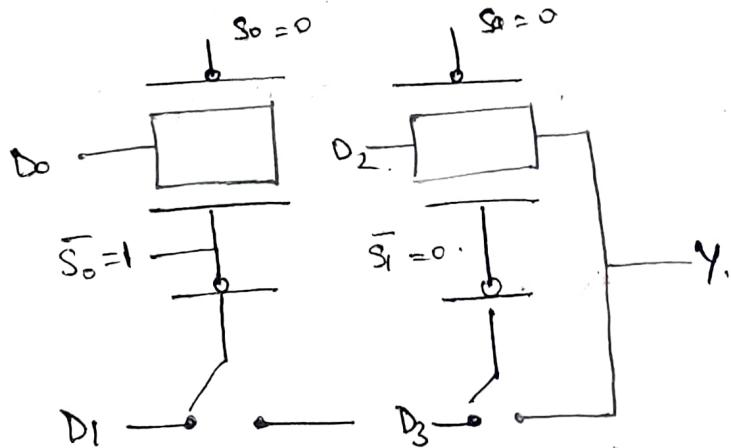
→ when $S_0 = 1$ & $S_1 = 1$, the i/p D_3 is selected and directed as o/p





when $S_0 = 0 + S_1 = 0$.

if p D_0 is selected and directed to opp. y .



when $S_0 = 0 + S_1 = 1$, if D_1 is selected and directed to the q

